

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10648289	HOSHINO ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Sherman, Stephen G	2629

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	173-178	10/27/2005	SS
178	18.01,20.01	10/27/2005	SS
715	701,702	11/2/2005	SS

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
See attached search history		
Search Updated	5/4/2006	SS
Search Updated	11/2/2006	SS
Search Updated	8/15/2007	SS
NPL Documents Searched (ACM,IEEE,INSPEC)	8/15/2007	SS

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	173-178	8/15/2007	SS
345	18.01,20.01	8/15/2007	SS
345	701,702	8/15/2007	SS
See attached search history			